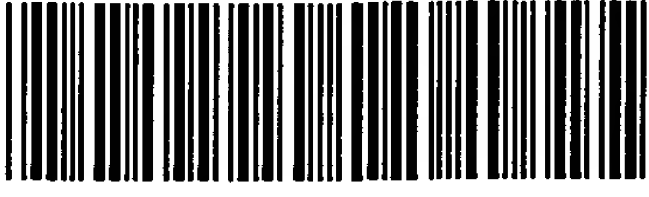


<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>	
	09/850,367	HA ET AL.	
	<b>Examiner</b>	<b>Art Unit</b>	
	HOAN C. NGUYEN	2871	

SEARCHED			
Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST (US Pat; US Pub; update search EP; JPO)	7/26/2005	CHN